


<b>Search Notes</b>  	<b>Application/Control No.</b>  10725432	<b>Applicant(s)/Patent Under Reexamination</b>  YI ET AL.
	<b>Examiner</b>  DJENANE M BAYARD	<b>Art Unit</b>  2444

SEARCHED			
Class	Subclass	Date	Examiner
709	250, 243	7/22/09	db
709	201, 203, 223, 224, 250	1/14/10	db
715	744, 746	1/14/10	db

SEARCH NOTES		
Search Notes	Date	Examiner
east	7/22/09	db
East	1/14/10	db
Double Patenting Search	1/14/10	db
NPL (google Scholar)	1/14/10	db
EIC (FAST and Focus Search)	1/14/10	db

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	201, 203, 223, 224, 250	1/14/10	db

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